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**Morley M. Blouke**  
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# Contents

vii Conference Committee

---

## SESSION 1 CCD IMAGERS

---

- 650102 **Evaluation of the 111-megapixel high speed high resolution CCD** [6501-01]  
K. Boggs, R. Bredthauer, G. Bredthauer, Semiconductor Technology Associates Inc. (USA)
- 650103 **Computation of dark frames in digital imagers** [6501-02]  
R. Widenhorn, Portland State Univ. (USA) and Digital Clarity Consultants (USA); A. Rest, Cerro Tololo Inter-American Observatory (USA); M. M. Blouke, Ball Aerospace & Technologies Corp. (USA); R. L. Berry, Digital Clarity Consultants (USA); E. Bodegom, Portland State Univ. (USA) and Digital Clarity Consultants (USA)
- 650104 **A novel pixel structure for 2  $\mu\text{m}$  square pixel IT-CCD** [6501-03]  
G. Sakoda, M. Sato, D. Sugimoto, K. Maari, S. Miyazawa, T. Takeda, M. Kimura, T. Fujioka, Sony Corp. (Japan); M. Fujishima, Y. Kani, Sony LSI Design Inc. (Japan); H. Kanbe, Sony Corp. (Japan)
- 650105 **Simulation for estimating smear noise and sensitivity of CCD image sensors having square pixels cells less than 2.0  $\mu\text{m}$**  [6501-04]  
K. Kikuchi, S. Miyazawa, Y. Uchida, H. Kamata, T. Hirayama, Sony Corp. (Japan)
- 650106 **Development of fully depleted scientific CCDs for astronomy** [6501-05]  
K. Boggs, R. Bredthauer, Semiconductor Technology Associates Inc. (USA); M. Lesser, Univ. of Arizona (USA)
- 650107 **Orthogonal transfer arrays for the Pan-STARRS gigapixel camera** [6501-41]  
B. E. Burke, MIT Lincoln Lab. (USA); J. L. Tonry, Univ. of Hawaii (USA); M. J. Cooper, P. E. Doherty, A. H. Loomis, D. J. Young, T. A. Lind, MIT Lincoln Lab. (USA); P. Onaka, Univ. of Hawaii (USA); D. J. Landers, P. J. Daniels, J. L. Daneu, MIT Lincoln Lab. (USA)
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The CID number appears on each page of the manuscript. The complete citation is used on the first page, and an abbreviated version on subsequent pages.

---

**SESSION 2 APPLICATIONS AND SYSTEMS I**

---

- 650108 **Improvement in photoelectric conversion efficiency of red light in HARP film** [6501-06]  
T. Matsubara, Y. Ohkawa, K. Miyakawa, S. Suzuki, M. Kubota, N. Egami, K. Tanioka, NHK Science & Technical Research Labs. (Japan); K. Ogsu, A. Kobayashi, T. Hirai, T. Kawai, Hamamatsu Photonics K.K. (Japan)
- 650109 **Bifocal liquid lens zoom objective for mobile phone applications** [6501-07]  
F. C. Wippermann, P. Schreiber, A. Bräuer, Fraunhofer Institute for Applied Optics and Precision Engineering (Germany); P. Craen, Varioptic SA (France)
- 65010A **The intermediate size direct detection detector for electron microscopy** [6501-08]  
L. Jin, A.-C. Milazzo, Univ. of California, San Diego (USA); S. Kleinfelder, S. Li, Univ. of California, Irvine (USA); P. Leblanc, F. Duttweiler, J. C. Bouwer, S. T. Peltier, M. Ellisman, N.-H. Xuong, Univ. of California, San Diego (USA)
- 65010B **A novel image acquisition system using the optical-multiplex system** [6501-09]  
T. Narabu, Sony Corp. (Japan)
- 65010D **Position detection with hyperacuity using artificial compound eyes** [6501-11]  
A. Brückner, J. Duparré, A. Bräuer, Fraunhofer Institute for Applied Optics and Precision Engineering (Germany); A. Tünnermann, Fraunhofer Institute for Applied Optics and Precision Engineering (Germany) and Friedrich-Schiller-Univ. Jena (Germany)
- 65010E **High-dynamic-range video for photometric measurement of illumination** [6501-12]  
J. Unger, S. Gustavson, Linköping Univ. (Sweden)
- 65010F **Thermal-imaging-based procedures for special concretes characterization** [6501-14]  
G. Bonifazi, M. Animali, L. Damiani, Univ. degli Studi di Roma La Sapienza (Italy)

---

**SESSION 3 CMOS SENSORS**

---

- 65010G **Shared transistor architecture with diagonally connected pixels for a CMOS image sensor** [6501-15]  
Y. Kudoh, F. Koga, T. Abe, H. Taniguchi, M. Sato, H. Ishiwata, S. Ooki, R. Suzuki, H. Mori, Sony Corp. (Japan)
- 65010H **Image sensor for object detection using modulated light** [6501-16]  
H. Taruki, A. Ohno, F. Ono, T. Hamamoto, Tokyo Univ. of Science (Japan); T. Sasaki, T. Shirai, M. Sakai, The Nippon Signal Co., Ltd. (Japan)
- 65010I **Linear-logarithmic image sensor with low noise and no flickers** [6501-17]  
S. Miyatake, M. Kusuda, T. Iwamoto, T. Katagiri, K. Kamon, K. Sato, Y. Serita, Konica Minolta Technology Ctr., Inc. (Japan)
- 65010K **Distance detective small camera module** [6501-19]  
I. Oyama, T. Iijima, K. Imada, S. Tamaki, T. Suenaga, N. Immura, T. Ota, M. Suzuki, M. Nagashima, Matsushita Electric Industrial Co., Ltd. (Japan)

- 65010L **A digital high-dynamic-range CMOS image sensor with multi-integration and pixel readout request** [6501-20]  
A. Guilvard, J. Segura, STMicroelectronics (France); P. Magnan, P. Martin-Gonthier, CIMI/Supaero (France)
- 65010N **Demonstration of a low-voltage three-transistor-per-pixel CMOS imager based on a pulse-width-modulation readout scheme employed with a one-transistor in-pixel comparator** [6501-22]  
S. Shishido, I. Nagahata, T. Sasaki, K. Kagawa, M. Nunoshita, J. Ohta, Nara Institute of Science and Technology (Japan)
- 65010O **A 960-fps sub-sampling object extraction CMOS image sensor with 12-bit column parallel ADCs and ALUs** [6501-23]  
Y. Motohashi, T. Kubo, H. Kanto, T. Tate, S. Sugawa, Tohoku Univ. (Japan)
- 65010P **A temperature resistant wide dynamic range CMOS image sensor** [6501-24]  
K. Mizobuchi, S. Adachi, T. Yamashita, S. Okamura, H. Oshikubo, Texas Instruments Japan (Japan); N. Akahane, S. Sugawa, Tohoku Univ. (Japan)

---

#### SESSION 4 SYSTEMS AND APPLICATIONS II

---

- 65010Q **Characterization and system modeling of a 5-Mpixel CMOS array** [6501-42]  
K. Cabanas-Holmen, D. Dorn, C. Tesdahl, Pelco (USA)
- 65010R **Low cost optical polarization sensor** [6501-26]  
D. P. Baxter, J. M. Raynor, J.-L. Jaffard, STMicroelectronics (United Kingdom); D. Renshaw, The Univ. of Edinburgh (United Kingdom)
- 65010S **A diffractive multispectral image sensor with on- and off-die signal processing and on-die optics in 0.18-micron CMOS** [6501-27]  
C. Thomas, R. Hornsey, York Univ. (Canada)
- 65010T **Diffraction grating lens array** [6501-28]  
T. Korenaga, T. Ando, S. Moriguchi, F. Takami, Y. Takasu, S. Nishiwaki, M. Suzuki, M. Nagashima, Matsushita Electric Industrial Co., Ltd. (Japan)

---

#### SESSION 5 NONDESTRUCTIVE TESTING

---

- 65010U **Critical assessment of the integrity of thin organic films by shearography** [6501-29]  
K. Habib, Kuwait Institute for Scientific Research (Kuwait)
- 65010W **Development of a wavelength-changeable multiband color-mixing imaging device and its application** [6501-40]  
F. Ding, Y.-R. Chen, K. Chao, D. E. Chan, USDA Agricultural Research Service (USA)

---

#### POSTER SESSION

---

- 65010Y **Qualitative measurement of average index profile of symmetrical microstructured optical fiber from microscopic imaging** [6501-32]  
E. Saucedo, V. P. Minkovich, Ctr. de Investigaciones en Optica, A.C. (Mexico)

- 65010Z **A practicable method for color classification using low-cost remission/reflection sensors**  
[6501-33]  
R. Hauser, Carinthia Univ. of Applied Sciences (Austria); I. Ibraheem, Carinthian Tech Research (Austria); C. V. Madritsch, N. Kabirpanthi, Carinthia Univ. of Applied Sciences (Austria); D. Römhild, D. Starke, CiS, Institut für Mikrosensorik GmbH (Germany); V. Mannheim, Carinthia Tech Research (Austria); W. Schwab, Carinthia Univ. of Applied Sciences (Austria); J. Krohn, J. Randa, Haukeland Univ. Hospital (Norway); T. Klinger, Carinthia Univ. of Applied Sciences (Austria)
- 650110 **A CMOS vision chip for a contrast-enhanced image using a logarithmic APS and a switch-selective resistive network** [6501-34]  
J.-S. Kong, S.-H. Kim, D.-K. Sung, S.-H. Seo, J.-K. Shin, Kyungpook National Univ. (South Korea)
- 650111 **Highly sensitive and area-efficient CMOS image sensor using a PMOSFET-type photodetector with a built-in transfer gate** [6501-35]  
S.-H. Seo, K.-D. Kim, J.-S. Kong, J.-K. Shin, P. Choi, Kyungpook National Univ. (South Korea)
- 650112 **Microscopic x-ray imaging system for biomedical applications using synchrotron radiation**  
[6501-37]  
K. Umetani, Japan Synchrotron Radiation Research Institute (Japan); M. Kobatake, A. Yamamoto, T. Yamashita, S. Imai, Kawasaki Medical School (Japan)
- 650114 **Sensor for moving foreground detection: an address-event-based embedded system**  
[6501-39]  
N. Milosevic, P. Schön, Austrian Research Ctrs. GmbH (Austria)

*Author Index*

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